

ABSTRACT OF THE DISCLOSURE

A profile measurement apparatus of the present invention is characterized in that two flash light beams, having wavelengths slightly different from each other, are emitted to an object with a predetermined interval t_1 therebetween, and when a camera picks up interference light formed by light beams reflected from the object and a light beam reflected from the reference mirror, while moving the object in a direction, in which the two flash light beams are directed, in units of intervals t_2 at which each of the two flash light beams is cyclically emitted, a phase shift amount corresponding to a movement amount of the object at a time is set to a value falling within a range of $2n\pi \pm \pi/2 \pm \pi/4$.